

## Systematic investigation of MR properties in CPP-GMR devices using $\text{Co}_2\text{Fe}_x\text{Mn}_{1-x}\text{Si}$ electrodes

IMR, Tohoku Univ., <sup>○</sup>Masaki Ueda, Yuya Sakuraba, Koki Takanashi

E-mail: m\_ueda@imr.tohoku.ac.jp

Current-perpendicular-to-plane giant magnetoresistance (CPP-GMR) devices are promising as a magnetic read sensor for next generation HDD. However, larger MR ratio is required for applying CPP-GMR devices to practical read sensors. Co-based full-Heusler compounds such as  $\text{Co}_2\text{MnSi}$  (CMS) are promising spintronics materials because of their half-metallic electronic structure. Previously, a large MR ratio around 36% at RT has been observed in CPP-GMR devices with CMS electrodes[1]. Recently, it was reported that the largest MR ratio of 75% at RT in CPP-GMR devices with  $\text{Co}_2\text{Fe}_{0.4}\text{Mn}_{0.6}\text{Si}$  (CFMS) electrodes[2]. However, the systematic investigation in CFMS-based CPP-GMR devices had been not reported. Therefore, we reported systematic investigation in CFMS-based CPP-GMR devices such as composition and measurement temperature dependences[3]. In this study, we investigate the annealing temperature dependence of CFMS or CMS-based CPP-GMR devices in addition to our previous study.

The CPP-GMR devices of  $\text{MgO}(001)\text{-sub.//Cr}(20)/\text{Ag}(40)/\text{CFMS}(20)/\text{Ag}(5)/\text{CFMS}(3)/\text{Ag}(2)/\text{Au}(5)$  and  $\text{MgO}(001)\text{-sub.//Cr}(20)/\text{Ag}(40)/\text{CMS}(9)/\text{Ag}(5)/\text{CMS}(9)/\text{Ag}(2)/\text{Au}(5)$  (in nm) were prepared by an ultra vacuum compatible magnetron sputtering system ( $P_{\text{base}} < 3 \times 10^{-8}$  Pa). The composition of CFMS was  $\text{Co}_2\text{Fe}_{0.5}\text{Mn}_{0.5}\text{Si}$  analyzed by EPMA. The annealing temperatures of each CFMS or CMS layers after the deposition were 350 to 625°C. The actual pillar sizes of the CPP-GMR devices of 0.010 to 0.366  $\mu\text{m}^2$  were strictly estimated.

Figure 1 shows the annealing temperature dependence of MR ratio in CFMS or CMS-based CPP-GMR devices. The MR ratio shown in Fig.1 is the maximum MR ratio including parasitic resistance arising from the electrode resistance. It is found that the MR ratio about 0% in the CMS-based CPP-GMR devices annealed at 600°C. We consider that it might be caused by the interdiffusion of Mn in CMS layers into/to the interface region of Ag spacer. On the other hand, the CFMS-based CPP-GMR devices still keep large MR ratio above 600°C. The reason may be the suppression of the interdiffusion by substituting Fe for Mn in CMS.

### Reference

- 1) Y. Sakuraba, *et al*, Phys. Rev. B **82**, 094444 (2010).
- 2) J. Sato, *et al*, Appl. Phys. Express **4**, 113005 (2011).
- 3) Y. Sakuraba, *et al*, Appl. Phys. Lett. **101**, 252408 (2012).

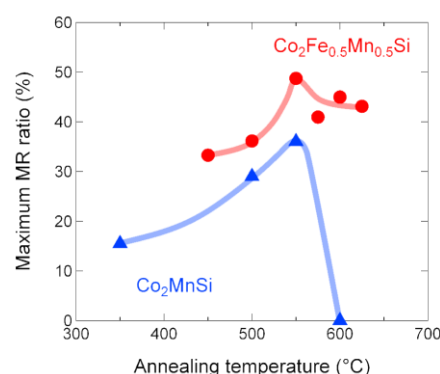


Fig.1 The annealing temperature dependence of MR ratio in CFMS or CMS-based CPP-GMR devices